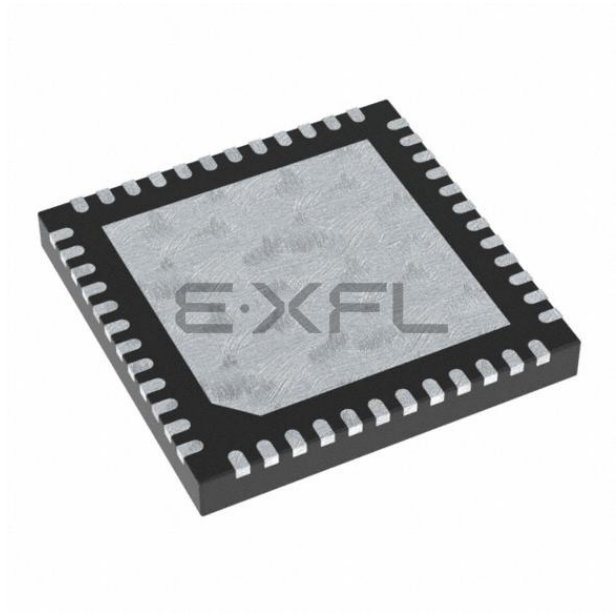

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, LCD, POR, PWM, WDT
Number of I/O	27
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.68V ~ 3.6V
Data Converters	A/D 3x12b; D/A 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atsam4lc4aa-mu

Table 3-2. 64-pin GPIO Controller Function Multiplexing (Sheet 3 of 3)

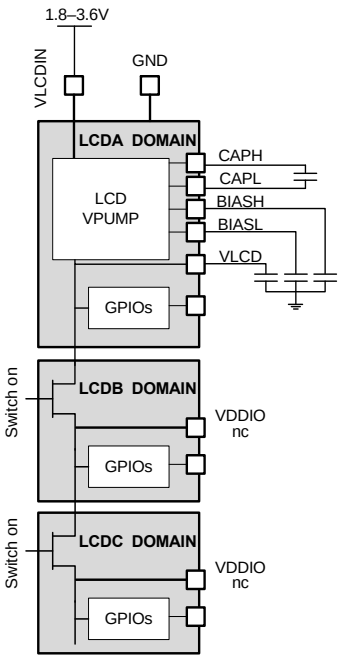
ATSAM4LC	ATSAM4LS	Pin	GPIO	Supply	GPIO Functions						
QFP QFN	QFP QFN				A	B	C	D	E	F	G
	33	PA27	27	LCDA	SPI MISO	IISC ISCK	ABDACB DAC0	GLOC IN4	USART3 RTS		CATB SENSE0
	34	PA28	28	LCDA	SPI MOSI	IISC ISDI	ABDACB DACN0	GLOC IN5	USART3 CTS		CATB SENSE1
	35	PA29	29	LCDA	SPI SCK	IISC IWS	ABDACB DAC1	GLOC IN6	USART3 CLK		CATB SENSE2
	38	PA30	30	LCDA	SPI NPCS0	IISC ISDO	ABDACB DACN1	GLOC IN7	USART3 RXD		CATB SENSE3
	39	PA31	31	LCDA	SPI NPCS1	IISC IMCK	ABDACB CLK	GLOC OUT1	USART3 TXD		CATB DIS
11	11	PB00	32	VDDIN	TWIMS1 TWD	USART0 RXD					CATB SENSE21
12	12	PB01	33	VDDIN	TWIMS1 TWCK	USART0 TXD	EIC EXTINT0				CATB SENSE22
13	13	PB02	34	VDDANA	ADCIFE AD3	USART1 RTS	ABDACB DAC0	IISC ISCK	ACIFC ACBN0		CATB SENSE23
14	14	PB03	35	VDDANA	ADCIFE AD4	USART1 CLK	ABDACB DACN0	IISC ISDI	ACIFC ACBP0		CATB DIS
19	19	PB04	36	VDDANA	ADCIFE AD5	USART1 RXD	ABDACB DAC1	IISC ISDO	DACC EXT TRIG0		CATB SENSE24
20	20	PB05	37	VDDANA	ADCIFE AD6	USART1 TXD	ABDACB DACN1	IISC IMCK			CATB SENSE25
27	27	PB06	38	LCDA	USART3 RTS		GLOC IN4	IISC IWS		LCDCA SEG22	CATB SENSE26
28	28	PB07	39	LCDA	USART3 CTS		GLOC IN5	TC0 A0		LCDCA SEG21	CATB SENSE27
45	45	PB08	40	LCDA	USART3 CLK		GLOC IN6	TC0 B0		LCDCA SEG14	CATB SENSE28
46	46	PB09	41	LCDA	USART3 RXD	PEVC PAD EVT2	GLOC IN7	TC0 A1		LCDCA SEG15	CATB SENSE29
47	47	PB10	42	LCDA	USART3 TXD	PEVC PAD EVT3	GLOC OUT1	TC0 B1	SCIF GCLK0	LCDCA SEG16	CATB SENSE30
48	48	PB11	43	LCDA	USART0 CTS	SPI NPCS2		TC0 A2	SCIF GCLK1	LCDCA SEG17	CATB SENSE31
53	53	PB12	44	LCDC	USART0 RTS	SPI NPCS3	PEVC PAD EVT0	TC0 B2	SCIF GCLK2	LCDCA SEG32	CATB DIS
54	54	PB13	45	LCDC	USART0 CLK	SPI NPCS1	PEVC PAD EVT1	TC0 CLK0	SCIF GCLK3	LCDCA SEG33	CATB SENSE0
57	57	PB14	46	LCDC	USART0 RXD	SPI MISO	TWIM3 TWD	TC0 CLK1	SCIF GCLK IN0	LCDCA SEG36	CATB SENSE1
58	58	PB15	47	LCDC	USART0 TXD	SPI MOSI	TWIM3 TWCK	TC0 CLK2	SCIF GCLK IN1	LCDCA SEG37	CATB SENSE2

connected to an external voltage source (1.8-3.6V). LCDB cluster is not available in 64 and 48 pin packages

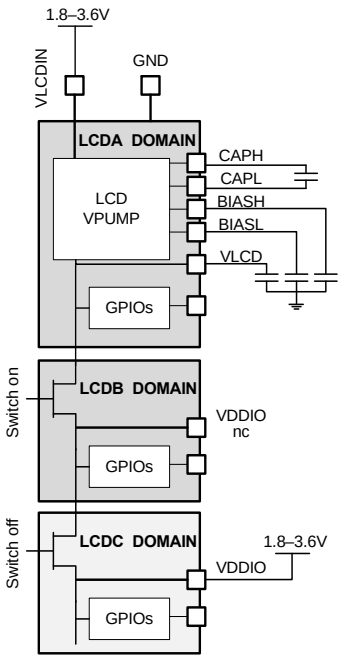
Table 6-1. LCD powering when using the internal voltage pump

Package	Segments in use	VDDIO LCDB	VDDIO LCDC
100-pin packages	[1,24]	1.8-3.6V	1.8-3.6V
	[1, 32]	nc	1.8-3.6V
	[1, 40]	nc	nc
64-pin packages	[1,15]	-	1.8-3.6V
	[1, 23]	-	nc
48-pin packages	[1,9]	-	1.8-3.6V
	[1,13]	-	nc

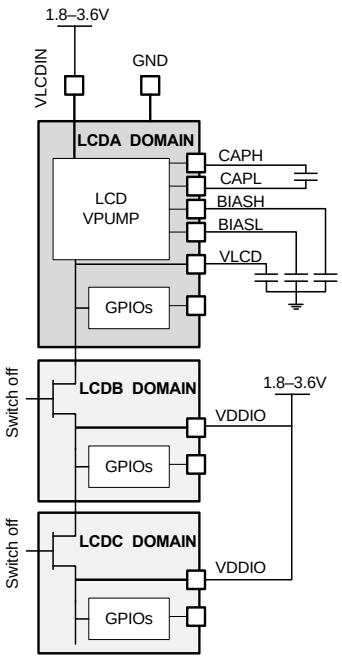
Up to 4x40 segments
No GPIO in LCD clusters



Up to 4x32 segments
Up to 8 GPIOs in LCDC clusters



Up to 4x24 segments
Up to 16 GPIOs in LCDB & LCDC clusters



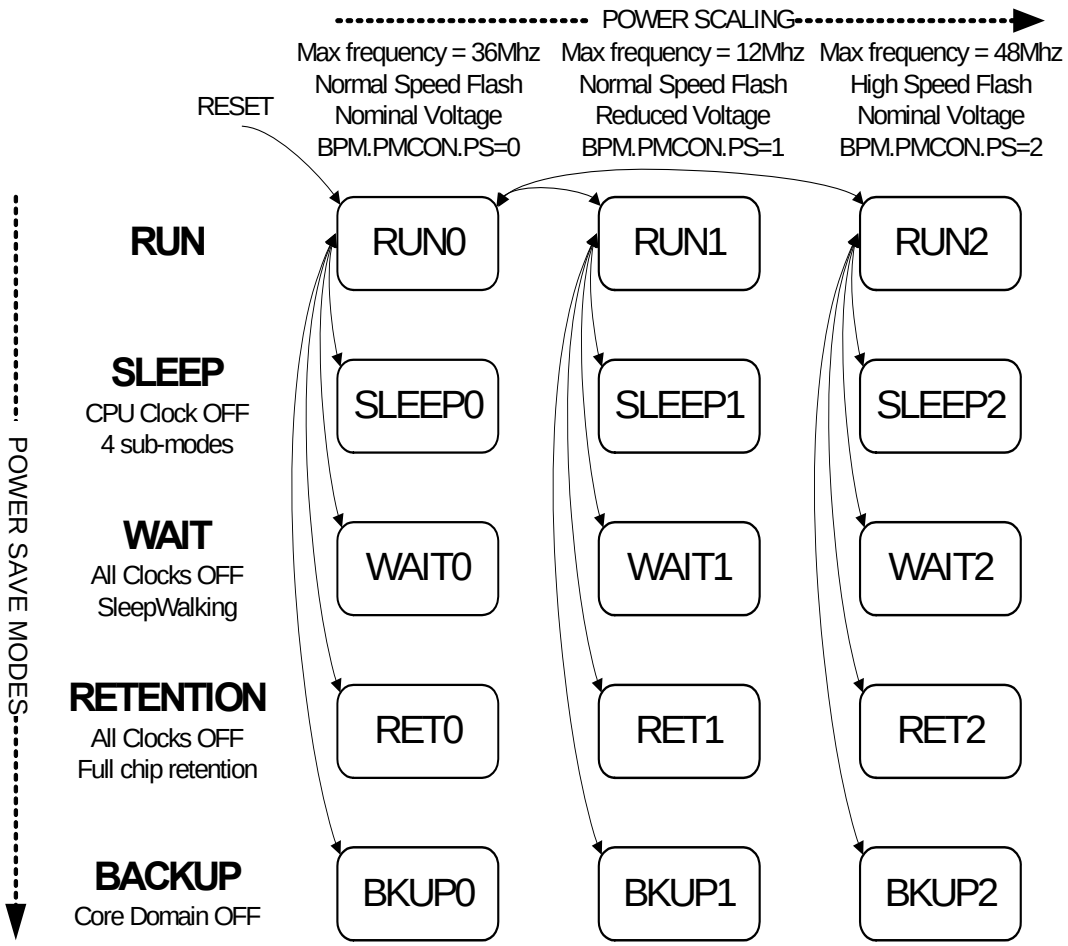
7. Low Power Techniques

The ATSAM4L8/L4/L2 supports multiple power configurations to allow the user to optimize its power consumption in different use cases. The Backup Power Manager (BPM) implements different solutions to reduce the power consumption:

- The Power Save modes intended to reduce the logic activity and to adapt the power configuration. See "Power Save Modes" on page 55.
- The Power Scaling intended to scale the power configuration (voltage scaling of the regulator). See "Power Scaling" on page 60.

These two techniques can be combined together.

Figure 7-1. Power Scaling and Power Save Mode Overview



7.1 Power Save Modes

Refer to Section 6. "Power and Startup Considerations" on page 46 to get definition of the core and the backup domains.

mechanism can be useful for applications that only require the processor to run when an interrupt occurs.

Before entering the SLEEP mode, the user must configure:

- the SLEEP mode configuration field (BPM.PMCON.SLEEP), Refer to Table 7-1.
- the SCR.SLEEPDEEP bit to 0. (See the Power Management section in the ARM Cortex-M4 Processor chapter).
- the BPM.PMCON.RET bit to 0.
- the BPM.PMCON.BKUP bit to 0.

7.1.1.2 Exiting SLEEP mode

The NVIC wakes the system up when it detects any non-masked interrupt with sufficient priority to cause exception entry. The system goes back to the RUN mode from which the SLEEP mode was entered. The CPU and affected modules are restarted. Note that even if an interrupt is enabled in SLEEP mode, it will not trigger if the source module is not clocked.

7.1.2 WAIT Mode and RETENTION Mode

The WAIT and RETENTION modes allow achieving very low power consumption while maintaining the Core domain powered-on. Internal SRAM and registers contents of the Core domain are preserved.

In these modes, all clocks are stopped except the 32kHz clocks (OSC32K, RC32K) which are kept running if enabled.

In RETENTION mode, the SleepWalking feature is not supported and must not be used.

7.1.2.1 Entering WAIT or RETENTION Mode

The WAIT or RETENTION modes are entered by executing the WFI instruction with the following settings:

- set the SCR.SLEEPDEEP bit to 1. (See the Power Management section in the ARM Cortex-M4 Processor chapter).
- set the BPM.PSAVE.BKUP bit to 0.
- set the BPM.PMCON.RET bit to RETENTION or WAIT mode.

SLEEPONEXIT feature is also available. See ”Entering SLEEP mode” on page 56.

7.1.2.2 Exiting WAIT or RETENTION Mode

In WAIT or RETENTION modes, synchronous clocks are stopped preventing interrupt sources from triggering. To wakeup the system, asynchronous wake up sources (AST, EIC, USBC ...) should be enabled in the peripheral (refer to the documentation of the peripheral). The PM.AWEN (Asynchronous Wake Up Enable) register should also be enabled for all peripheral except for EIC and AST.

When the enabled asynchronous wake up event occurs and the system is waken-up, it will generate either:

- an interrupt on the PM WAKE interrupt line if enabled (Refer to Section 9. ”Power Manager (PM)” on page 677). In that case, the PM.WCAUSE register indicates the wakeup source.
- or an interrupt directly from the peripheral if enabled (Refer to the section of the peripheral).

When waking up, the system goes back to the RUN mode mode from which the WAIT or RETENTION mode was entered.

8.5 Product dependencies

8.5.1 I/O Lines

Refer to Section 1.1.5.1 ”I/O Lines” on page 5.

8.5.2 Power management

Refer to Section 1.1.5.2 ”Power Management” on page 5.

8.5.3 Clocks

Refer to Section 1.1.5.3 ”Clocks” on page 5.

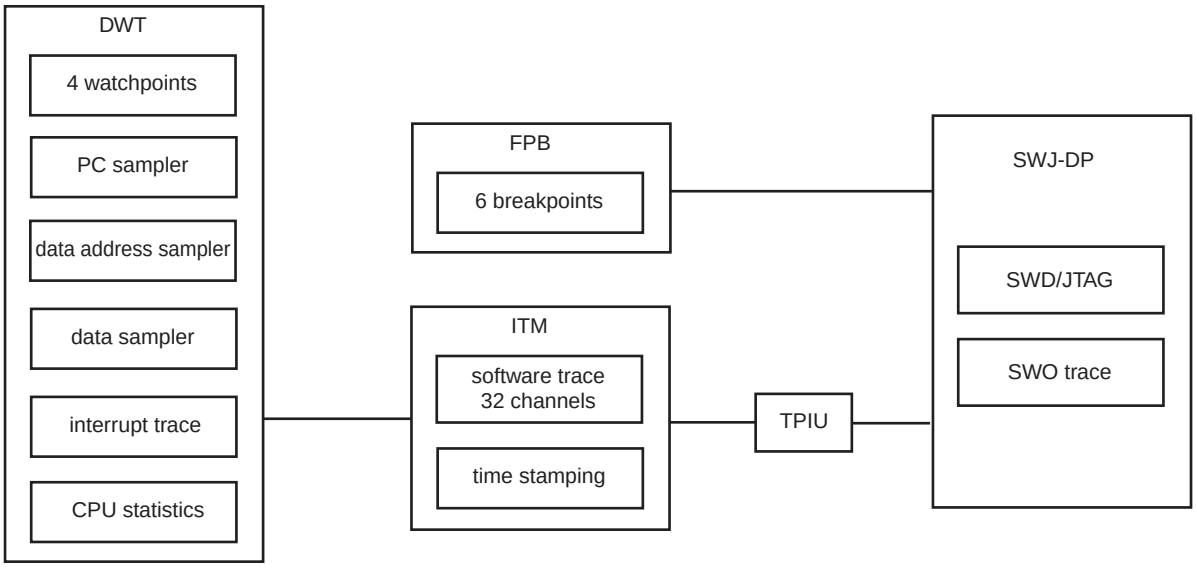
8.6 Core debug

Figure 8-2 shows the Debug Architecture used in the SAM4L. The Cortex-M4 embeds four functional units for debug:

- FPB (Flash Patch Breakpoint)
- DWT (Data Watchpoint and Trace)
- ITM (Instrumentation Trace Macrocell)
- TPIU (Trace Port Interface Unit)

The debug architecture information that follows is mainly dedicated to developers of SWJ-DP Emulators/Probes and debugging tool vendors for Cortex-M4 based microcontrollers. For further details on SWJ-DP see the Cortex-M4 technical reference manual.

Figure 8-2. Debug Architecture



8.6.1 FPB (Flash Patch Breakpoint)

The FPB:

- Implements hardware breakpoints
- Patches (on the fly) code and data being fetched by the Cortex-M4 core from code space with data in the system space. Definition of code and system spaces can be found in the System Address Map section of the ARMv7-M Architecture Reference Manual.

The FPB unit contains:

- Two literal comparators for matching against literal loads from Code space, and remapping to a corresponding area in System space.
- Six instruction comparators for matching against instruction fetches from Code space and remapping to a corresponding area in System space.
- Alternatively, comparators can also be configured to generate a Breakpoint instruction to the processor core on a match.

8.6.2 DWT (Data Watchpoint and Trace)

The DWT contains four comparators which can be configured to generate the following:

- PC sampling packets at set intervals
- PC or Data watchpoint packets
- Watchpoint event to halt core

The DWT contains counters for the items that follow:

- Clock cycle (CYCCNT)
- Folded instructions
- Load Store Unit (LSU) operations
- Sleep Cycles
- CPI (all instruction cycles except for the first cycle)
- Interrupt overhead

8.6.3 ITM (Instrumentation Trace Macrocell)

The ITM is an application driven trace source that supports printf style debugging to trace Operating System (OS) and application events, and emits diagnostic system information. The ITM emits trace information as packets which can be generated by three different sources with several priority levels:

- **Software trace**: This can be done thanks to the printf style debugging. For more information, refer to Section "How to Configure the ITM:".
- **Hardware trace**: The ITM emits packets generated by the DWT.
- **Time stamping**: Timestamps are emitted relative to packets. The ITM contains a 21-bit counter to generate the timestamp.

How to Configure the ITM:

The following example describes how to output trace data in asynchronous trace mode.

- Configure the TPIU for asynchronous trace mode (refer to Section "5.4.3. How to Configure the TPIU")
- Enable the write accesses into the ITM registers by writing "0xC5ACCE55" into the Lock Access Register (Address: 0xE0000FB0)
- Write 0x00010015 into the Trace Control Register:
  - Enable ITM
  - Enable Synchronization packets
  - Enable SWO behavior

8.9.11.6 Data Register

Name: DATA

Access Type: Read/Write

Offset: 0x14

Reset Value: 0x00000000

31	30	29	28	27	26	25	24
DATA							

23	22	21	20	19	18	17	16
DATA							

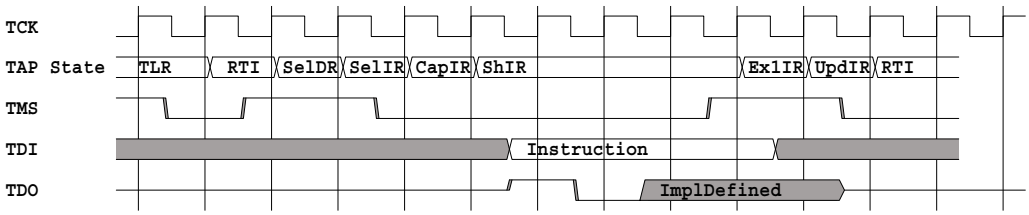
15	14	13	12	11	10	9	8
DATA							

7	6	5	4	3	2	1	0
DATA							

- **DATA: Generic data register**

Apply the TMS sequence 1, 1, 0 to re-enter the Run-Test/Idle state. The instruction is latched onto the parallel output from the shift register path in the Update-IR state. The Exit-IR, Pause-IR, and Exit2-IR states are only used for navigating the state machine.

Figure 8-10. Scanning in JTAG instruction



8.11.5.2 Scanning in/out data

At the TMS input, apply the sequence 1, 0, 0 at the rising edges of TCK to enter the Shift Data Register - Shift-DR state. While in this state, upload the selected Data Register (selected by the present JTAG instruction in the JTAG Instruction Register) from the TDI input at the rising edge of TCK. In order to remain in the Shift-DR state, the TMS input must be held low. While the Data Register is shifted in from the TDI pin, the parallel inputs to the Data Register captured in the Capture-DR state is shifted out on the TDO pin.

Apply the TMS sequence 1, 1, 0 to re-enter the Run-Test/Idle state. If the selected Data Register has a latched parallel-output, the latching takes place in the Update-DR state. The Exit-DR, Pause-DR, and Exit2-DR states are only used for navigating the state machine.

As shown in the state diagram, the Run-Test/Idle state need not be entered between selecting JTAG instruction and using Data Registers.

8.11.6 Boundary-Scan

The Boundary-Scan chain has the capability of driving and observing the logic levels on the digital I/O pins, as well as the boundary between digital and analog logic for analog circuitry having off-chip connections. At system level, all ICs having JTAG capabilities are connected serially by the TDI/TDO signals to form a long shift register. An external controller sets up the devices to drive values at their output pins, and observe the input values received from other devices. The controller compares the received data with the expected result. In this way, Boundary-Scan provides a mechanism for testing interconnections and integrity of components on Printed Circuits Boards by using the 4 TAP signals only.

The four IEEE 1149.1 defined mandatory JTAG instructions IDCODE, BYPASS, SAMPLE/PRELOAD, and EXTEST can be used for testing the Printed Circuit Board. Initial scanning of the data register path will show the ID-code of the device, since IDCODE is the default JTAG instruction. It may be desirable to have the device in reset during test mode. If not reset, inputs to the device may be determined by the scan operations, and the internal software may be in an undetermined state when exiting the test mode. Entering reset, the outputs of any Port Pin will instantly enter the high impedance state, making the HIGHZ instruction redundant. If needed, the BYPASS instruction can be issued to make the shortest possible scan chain through the device. The device can be set in the reset state by pulling the external RESET_N pin low.

The EXTEST instruction is used for sampling external pins and loading output pins with data. The data from the output latch will be driven out on the pins as soon as the EXTEST instruction is loaded into the JTAG IR-register. Therefore, the SAMPLE/PRELOAD should also be used for setting initial values to the scan ring, to avoid damaging the board when issuing the EXTEST

instruction for the first time. SAMPLE/PRELOAD can also be used for taking a snapshot of the external pins during normal operation of the part.

When using the JTAG interface for Boundary-Scan, the JTAG TCK clock is independent of the internal chip clock, which is not required to run.

NOTE: For pins connected to 5V lines care should be taken to not drive the pins to a logic one using boundary scan, as this will create a current flowing from the 3,3V driver to the 5V pullup on the line. Optionally a series resistor can be added between the line and the pin to reduce the current.

8.11.7 Flash Programming typical procedure

Flash programming is performed by operating Flash controller commands. The Flash controller is connected to the system bus matrix and is then controllable from the AHP-AP. The AHB-AP cannot write the FLASH page buffer while the core_hold_reset is asserted. The AHB-AP cannot be accessed when the device is in protected state. It is important to ensure that the CPU is halted prior to operating any flash programming operation to prevent it from corrupting the system configuration. The recommended sequence is shown below:

1. At power up, RESET_N is driven low by a debugger. The on-chip regulator holds the system in a POR state until the input supply is above the POR threshold. The system continues to be held in this static state until the internally regulated supplies have reached a safe operating.
2. PM starts, clocks are switched to the slow clock (Core Clock, System Clock, Flash Clock, and any Bus Clocks that do not have clock gate control). Internal resets are maintained due to the external reset.
   – The Debug Port (DP) and Access Ports (AP) receives a clock and leave the reset state,
3. The debugger maintains a low level on TCK and release RESET_N.
   – The SMAP asserts the core_hold_reset signal
4. The Cortex-M4 core remains in reset state, meanwhile the rest of the system is released.
5. The debugger then configures the NVIC to catch the Cortex-M4 core reset vector fetch. For more information on how to program the NVIC, refer to the ARMv7-M Architecture Reference Manual.
6. The debugger writes a one in the SMAP SCR.HCR to release the Cortex-M4 core reset to make the system bus matrix accessible from the AHB-AP.
7. The Cortex-M4 core initializes the SP, then read the exception vector and stalls
8. Programming is available through the AHB-AP
9. After operation is completed, the chip can be restarted either by asserting RESET_N or switching power off/on or clearing SCR.HCR. Make sure that the TCK pin is high when releasing RESET_N not to halt the core.

Table 9-6. ATSAM4L4/2 Current consumption and Wakeup time for power scaling mode 0 and 2

Mode	Conditions	T_A	Typical Wakeup Time	Typ	Max (1)	Unit
SLEEP0	Switching mode	25°C	9 * Main clock cycles	3817	4033	µA
		85°C		3934	4174	
SLEEP1	Switching mode	25°C	9 * Main clock cycles + 500ns	2341	2477	
		85°C		2437	2585	
SLEEP2	Switching mode	25°C	9 * Main clock cycles + 500ns	1758	1862	
		85°C		1847	1971	
SLEEP3	Linear mode	25°C		51	60	
WAIT	OSC32K and AST running Fast wake-up enable		1.5µs	5.9	8.7	
	OSC32K and AST stopped Fast wake-up enable			4.7	7.6	
RETENTION	OSC32K running AST running at 1kHz		1.5µs	3.1	5.1	
	AST and OSC32K stopped			2.2	4.2	
BACKUP	OSC32K running AST running at 1kHz			1.5	3.1	
	AST and OSC32K stopped			0.9	1.7	

1. These values are based on characterization. These values are not covered by test limits in production.

Table 9-7. ATSAM4L8 Current consumption and Wakeup time for power scaling mode 0 and 2

Mode	Conditions	T_A	Typical Wakeup Time	Typ	Max (1)	Unit
RUN	CPU running a Fibonacci algorithm Linear mode	25°C	N/A	319	343	µA/MHz
		85°C		326	350	
	CPU running a CoreMark algorithm Linear mode	25°C	N/A	343	387	
		85°C		351	416	
	CPU running a Fibonacci algorithm Switching mode	25°C	N/A	181	198	
		85°C		186	203	
	CPU running a CoreMark algorithm Switching mode	25°C	N/A	192	232	
		85°C		202	239	

– All other peripheral clocks stopped
- I/Os are inactive with internal pull-up
- CPU is running on flash with 1 wait state
- Low power cache enabled
- BOD18 and BOD33 disabled

Table 9-8. ATSAM4L4/2 Current consumption and Wakeup time for power scaling mode 1

Mode	Conditions	T_A	Typical Wakeup Time	Typ	Max (1)	Unit
RUN	CPU running a Fibonacci algorithm Linear mode	25°C	N/A	205	224	µA/MHz
		85°C		212	231	
	CPU running a CoreMark algorithm Linear mode	25°C	N/A	213	244	
		85°C		230	270	
	CPU running a Fibonacci algorithm Switching mode	25°C	N/A	95	112	
		85°C		100	119	
	CPU running a CoreMark algorithm Switching mode	25°C	N/A	100	128	
		85°C		107	138	
SLEEP0	Switching mode	25°C	9 * Main clock cycles	527	627	µA
		85°C		579	739	
SLEEP1	Switching mode	25°C	9 * Main clock cycles + 500ns	369	445	
		85°C		404	564	
SLEEP2	Switching mode	25°C	9 * Main clock cycles + 500ns	305	381	
		85°C		334	442	
SLEEP3	Linear mode	25°C		46	55	
WAIT	OSC32K and AST running Fast wake-up enable		1.5µs	4.7	7.5	
	OSC32K and AST stopped Fast wake-up enable			3.5	6.3	
RETENTION	OSC32K running AST running at 1kHz		1.5µs	2.6	4.8	
	AST and OSC32K stopped			1.5	4	
BACKUP	OSC32K running AST running at 1kHz			1.5	3.1	
	AST and OSC32K stopped			0.9	1.7	

1. These values are based on characterization. These values are not covered by test limits in production.

9.6 I/O Pin Characteristics

9.6.1 Normal I/O Pin

Table 9-13. Normal I/O Pin Characteristics (1)

Symbol	Parameter	Conditions		Min	Typ	Max	Units
R_{PULLUP}	Pull-up resistance (2)				40		kΩ
$R_{PULLDOWN}$	Pull-down resistance(2)				40		kΩ
V_{IL}	Input low-level voltage			-0.3		0.2 * V_{VDD}	V
V_{IH}	Input high-level voltage			0.8 * V_{VDD}		V_{VDD} + 0.3	V
V_{OL}	Output low-level voltage					0.4	V
V_{OH}	Output high-level voltage			V_{VDD} - 0.4			V
I_{OL}	Output low-level current (3)	ODCR0=0	1.68V<V_{VDD}<2.7V			0.8	mA
			2.7V<V_{VDD}<3.6V			1.6	mA
		ODCR0=1	1.68V<V_{VDD}<2.7V			1.6	mA
			2.7V<V_{VDD}<3.6V			3.2	mA
I_{OH}	Output high-level current(3)	ODCR0=0	1.68V<V_{VDD}<2.7V			0.8	mA
			2.7V<V_{VDD}<3.6V			1.6	mA
		ODCR0=1	1.68V<V_{VDD}<2.7V			1.6	mA
			2.7V<V_{VDD}<3.6V			3.2	mA
t_{RISE}	Rise time(2)	OSRR0=0	ODCR0=0 1.68V<V_{VDD}<2.7V, load = 25pF			35	ns
		OSRR0=1				45	ns
		OSRR0=0	ODCR0=0 2.7V<V_{VDD}<3.6V, load = 25pF			19	ns
		OSRR0=1				23	ns
t_{FALL}	Fall time(2)	OSRR0=0	ODCR0=0 1.68V<V_{VDD}<2.7V, load = 25pF			36	ns
		OSRR0=1				47	ns
		OSRR0=0	ODCR0=0 2.7V<V_{VDD}<3.6V, load = 25pF			20	ns
		OSRR0=1				24	ns
F_{PINMAX}	Output frequency(2)	OSRR0=0	ODCR0=0, V_{VDD}>2.7V load = 25pF			17	MHz
		OSRR0=1				15	MHz
		OSRR0=0	ODCR0=1, V_{VDD}>2.7V load = 25pF			27	MHz
		OSRR0=1				23	MHz
I_{LEAK}	Input leakage current(3)		Pull-up resistors disabled		0.01	1	µA
C_{IN}	Input capacitance(2)				5		pF

1. V_{VDD} corresponds to either V_{VDDIN} or V_{VDDIO}, depending on the supply for the pin. Refer to Section 3-5 on page 13 for details
2. These values are based on simulation. These values are not covered by test limits in production or characterization

9.7.7 1MHz RC Oscillator (RC1M) Characteristics

Table 9-30. RC1M Oscillator Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{OUT}	Output frequency (1)		0.91	1	1.12	MHz
I_{RC1M}	Current consumption (2)			35		µA
Duty	Duty cycle(1)		48.6	49.9	54.4	%

1. These values are based on characterization. These values are not covered by test limits in production.
2. These values are based on simulation. These values are not covered by test limits in production or characterization.

9.7.8 4/8/12MHz RC Oscillator (RCFAST) Characteristics

Table 9-31. RCFAST Oscillator Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{OUT}	Output frequency (1)	Calibrated, FRANGE=0	4	4.3	4.6	MHz
		Calibrated, FRANGE=1	7.8	8.2	8.5	
		Calibrated, FRANGE=2	11.3	12	12.3	
I_{RCFAST}	Current consumption (2)	Calibrated, FRANGE=0		90	110	µA
		Calibrated, FRANGE=1		130	150	
		Calibrated, FRANGE=2		180	205	
Duty	Duty cycle(1)	Calibrated, FRANGE=0	48.8	49.6	50.1	%
		Calibrated, FRANGE=1	47.8	49.2	50.1	
		Calibrated, FRANGE=2	46.7	48.8	50.0	
$t_{STARTUP}$	Startup time(1)	Calibrated, FRANGE=2	0.1	0.31	0.71	µs

1. These values are based on characterization. These values are not covered by test limits in production.
2. These values are based on simulation. These values are not covered by test limits in production or characterization.

1. These values are based on simulation. These values are not covered by test limits in production or characterization.

The values in Table 9-43 describe the values of the BOD33.LEVEL in the flash User Page fuses.

Table 9-43. BOD33.LEVEL Values

BOD33.LEVEL Value	Min	Typ	Max	Units
16		2.08		V
20		2.18		
24		2.33		
28		2.48		
32		2.62		
36		2.77		
40		2.92		
44		3.06		
48		3.21		

Table 9-44. BOD33 Characteristics (1)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
	Step size, between adjacent values in BSCIF.BOD33LEVEL(1)			34.4		mV
V_{HYST}	Hysteresis(1)		45		170	
t_{DET}	Detection time(1)	Time with VDDIN < V_{TH} necessary to generate a reset signal				µs
I_{BOD33}	Current consumption(1)	Normal mode			36	µA
$t_{STARTUP}$	Startup time(1)	Normal mode			6	µs

1. These values are based on simulation. These values are not covered by test limits in production or characterization.

Figure 9-10. USART in SPI Slave Mode with (CPOL= CPHA= 0) or (CPOL= CPHA= 1)

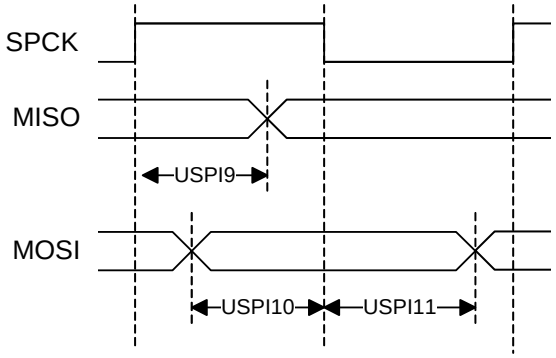


Figure 9-11. USART in SPI Slave Mode, NPCS Timing

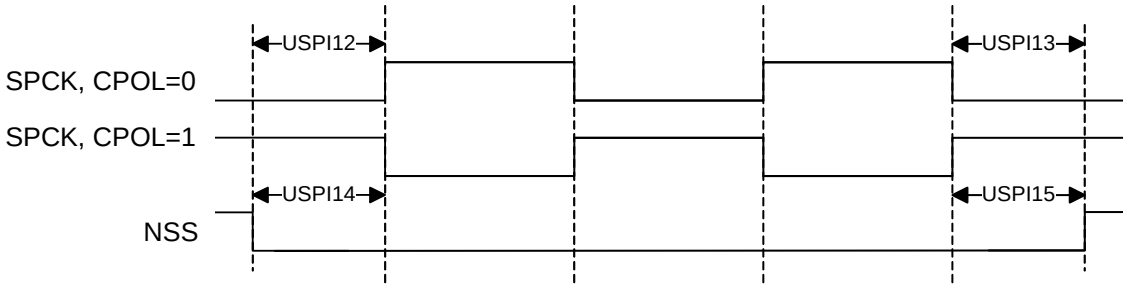


Table 9-58. USART0 in SPI mode Timing, Slave Mode[1]

Symbol	Parameter	Conditions	Min	Max	Units
USPI6	SPCK falling to MISO delay	V_{VDDIO} from 3.0V to 3.6V, maximum external capacitor = 40pF		740.67	ns
USPI7	MOSI setup time before SPCK rises		56.73 + t_{SAMPLE}[2] + t_{CLK_USART}		
USPI8	MOSI hold time after SPCK rises		45.18 -(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI9	SPCK rising to MISO delay			670.18	
USPI10	MOSI setup time before SPCK falls		56.73 +(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI11	MOSI hold time after SPCK falls		45.18 -(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI12	NSS setup time before SPCK rises		688.71		
USPI13	NSS hold time after SPCK falls		-2.25		
USPI14	NSS setup time before SPCK falls		688.71		
USPI15	NSS hold time after SPCK rises		-2.25		

Table 9-61. USART3 in SPI mode Timing, Slave Mode[1]

Symbol	Parameter	Conditions	Min	Max	Units
USPI6	SPCK falling to MISO delay	V_{VDDIO} from 3.0V to 3.6V, maximum external capacitor = 40pF		593.9	ns
USPI7	MOSI setup time before SPCK rises		45.93 + t_{SAMPLE}[2] + t_{CLK_USART}		
USPI8	MOSI hold time after SPCK rises		47.03 -(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI9	SPCK rising to MISO delay			593.38	
USPI10	MOSI setup time before SPCK falls		45.93 +(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI11	MOSI hold time after SPCK falls		47.03 -(t_{SAMPLE}[2] + t_{CLK_USART})		
USPI12	NSS setup time before SPCK rises		237.5		
USPI13	NSS hold time after SPCK falls		-1.81		
USPI14	NSS setup time before SPCK falls		237.5		
USPI15	NSS hold time after SPCK rises		-1.81		

Notes: 1. These values are based on simulation. These values are not covered by test limits in production.

2. Where: $t_{SAMPLE} = t_{SPCK} - \left(\left\lfloor \frac{t_{SPCK}}{2 \times t_{CLKUSART}} \right\rfloor + \frac{1}{2}\right) \times t_{CLKUSART}$

Maximum SPI Frequency, Slave Input Mode

The maximum SPI slave input frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(\frac{f_{CLKSPI} \times 2}{9}, \frac{1}{SPIn})$$

Where $SPIn$ is the MOSI setup and hold time, USPI7 + USPI8 or USPI10 + USPI11 depending on CPOL and NCPHA. f_{CLKSPI} is the maximum frequency of the CLK_SPI. Refer to the SPI chapter for a description of this clock.

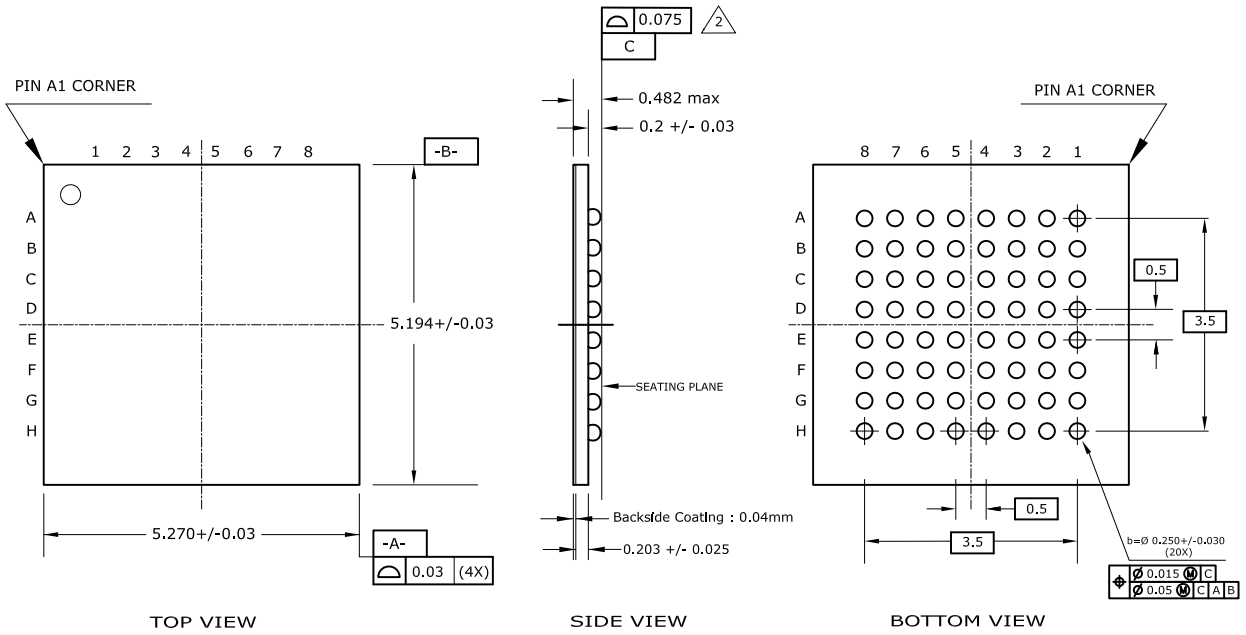
Maximum SPI Frequency, Slave Output Mode

The maximum SPI slave output frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(\frac{f_{CLKSPI} \times 2}{9}, f_{PINMAX}, \frac{1}{SPIn + t_{SETUP}})$$

Where $SPIn$ is the MISO delay, USPI6 or USPI9 depending on CPOL and NCPHA. T_{SETUP} is the SPI master setup time. refer to the SPI master datasheet for T_{SETUP} . f_{CLKSPI} is the maximum frequency of the CLK_SPI. Refer to the SPI chapter for a description of this clock. f_{PINMAX} is the maximum frequency of the SPI pins. refer to the I/O Pin Characteristics section for the maximum frequency of the pins.

Figure 10-6. WLCSP64 SAM4LS8 Package Drawing



COMMON DIMENSIONS
(Unit of Measure = mm)

BALL	SIGNAL	X COORD	Y COORD
A1	PB04	1.75	1.75
A2	GNDANA	1.75	1.25
A3	ADVREFP	1.75	0.75
A4	VDDANA	1.75	0.25
A5	PA09	1.75	-0.25
A6	PA28	1.75	-0.75
A7	PA27	1.75	-1.25
A8	PA12	1.75	-1.75
B1	PB03	1.25	1.75
B2	XIN32	1.25	1.25
B3	XOUT32	1.25	0.75
B4	PA08	1.25	0.25
B5	PB06	1.25	-0.25
B6	PA10	1.25	-0.75
B7	PA11	1.25	-1.25
B8	PA29	1.25	-1.75
C1	VDDIN	0.75	1.75
C2	PB01	0.75	1.25
C3	PA05	0.75	0.75
C4	PA06	0.75	0.25
C5	PA07	0.75	-0.25
C6	PB07	0.75	-0.75

BALL	SIGNAL	X COORD	Y COORD
C7	PA13	0.75	-1.25
C8	GNDIO0	0.75	-1.75
D1	VDDOUT	0.25	1.75
D2	PB00	0.25	1.25
D3	PA04	0.25	0.75
D4	PB05	0.25	0.25
D5	PB12	0.25	-0.25
D6	PB08	0.25	-0.75
D7	PA14	0.25	-1.25
D8	VLCDIN	0.25	-1.75
E1	GNDIN	-0.25	1.75
E2	PA03	-0.25	1.25
E3	PB02	-0.25	0.75
E4	RESET_N	-0.25	0.25
E5	PB13	-0.25	-0.25
E6	PB09	-0.25	-0.75
E7	PA15	-0.25	-1.25
E8	PA30	-0.25	-1.75
F1	VDDCORE	-0.75	1.75
F2	TCK	-0.75	1.25
F3	PA02	-0.75	0.75
F4	PB14	-0.75	0.25

BALL	SIGNAL	X COORD	Y COORD
F5	PA22	-0.75	-0.25
F6	PB10	-0.75	-0.75
F7	PA16	-0.75	-1.25
F8	PA31	-0.75	-1.75
G1	GNDIO1	-1.25	1.75
G2	PA26	-1.25	1.25
G3	PA24	-1.25	0.75
G4	PA00	-1.25	0.25
G5	PA01	-1.25	-0.25
G6	PA19	-1.25	-0.75
G7	PA18	-1.25	-1.25
G8	PA17	-1.25	-1.75
H1	VDDIO1	-1.75	1.75
H2	PA25	-1.75	1.25
H3	PA23	-1.75	0.75
H4	PB15	-1.75	0.25
H5	PA21	-1.75	-0.25
H6	VDDIO0	-1.75	-0.75
H7	PA20	-1.75	-1.25
H8	PB11	-1.75	-1.75

Notes : 1. Dimension "b" is measured at the maximum ball diameter in a plane to the seating plane.

2. Applied to whole wafer.

Table 10-17. Device and Package Maximum Weight

14.8	mg

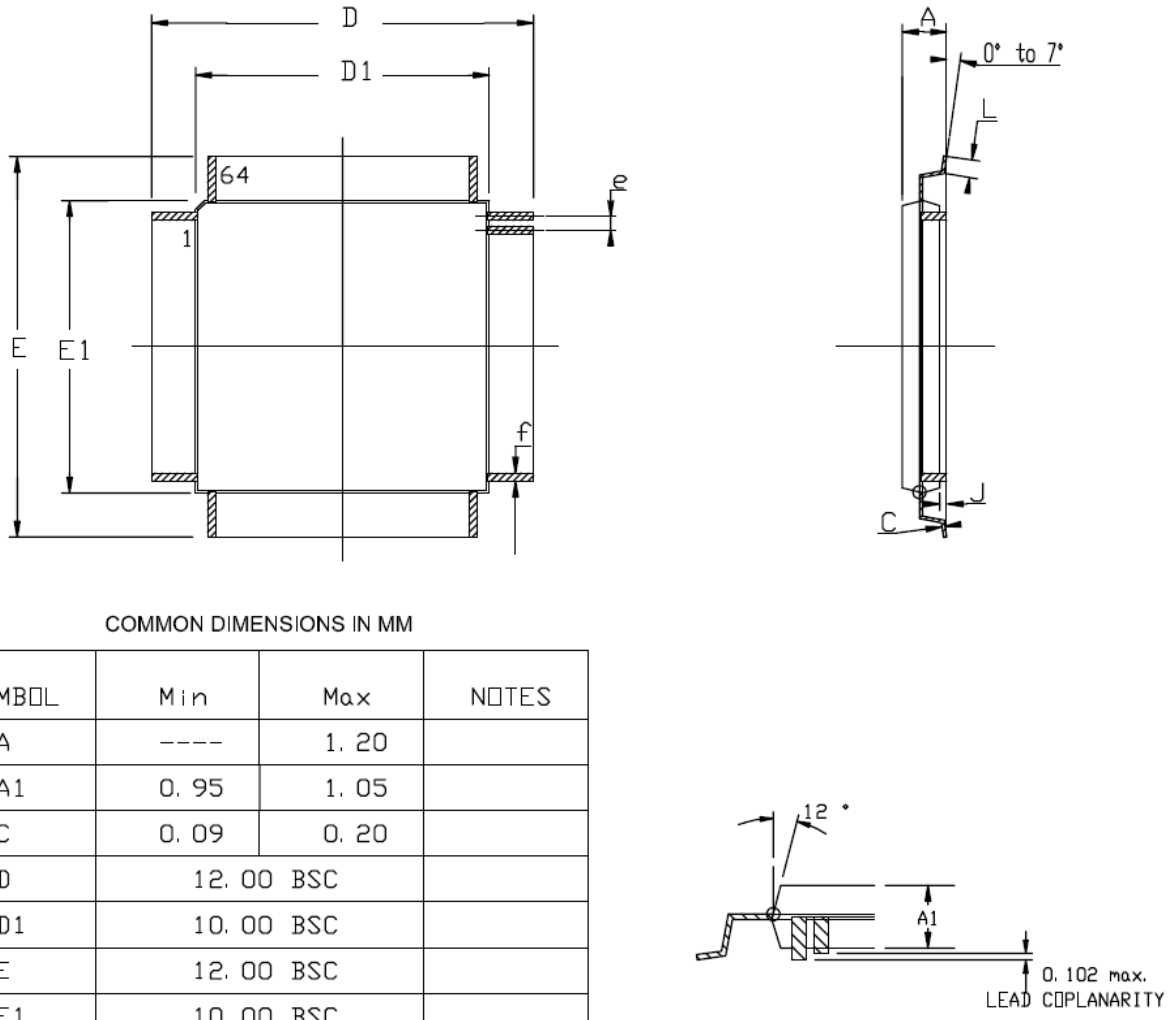
Table 10-18. Package Characteristics

Moisture Sensitivity Level	MSL3

Table 10-19. Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E1

Figure 10-7. TQFP-64 Package Drawing



COMMON DIMENSIONS IN MM

SYMBOL	Min	Max	NOTES
A	----	1.20	
A1	0.95	1.05	
C	0.09	0.20	
D	12.00 BSC		
D1	10.00 BSC		
E	12.00 BSC		
E1	10.00 BSC		
J	0.05	0.15	
L	0.45	0.75	
e	0.50 BSC		
f	0.17	0.27	

Table 10-20. Device and Package Maximum Weight

300	mg

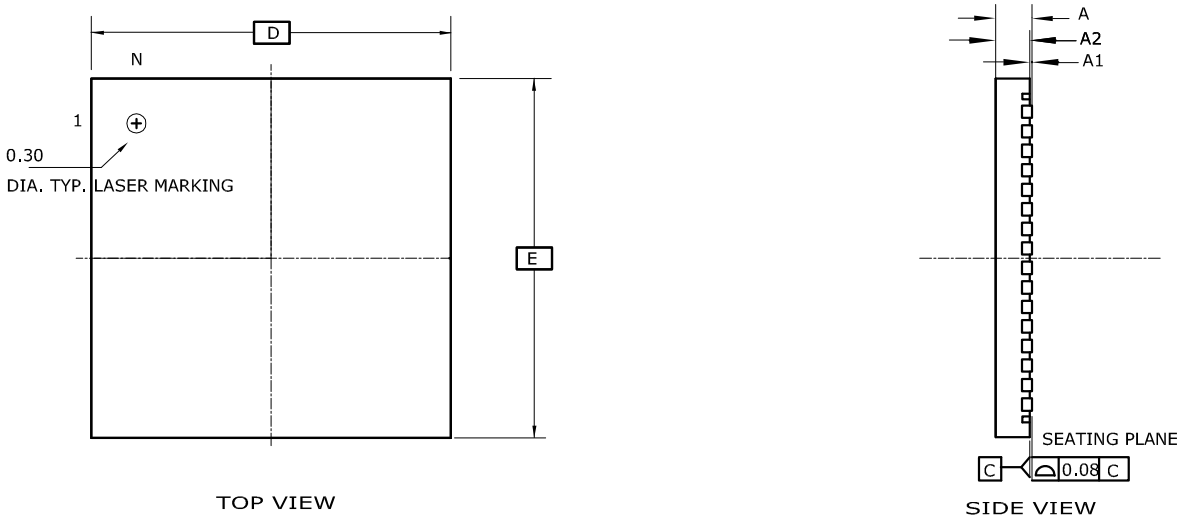
Table 10-21. Package Characteristics

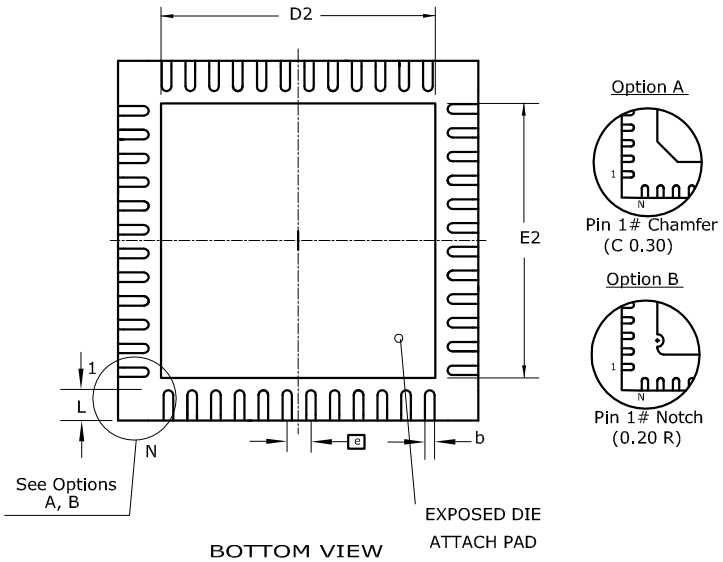
Moisture Sensitivity Level	MSL3

Table 10-22. Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E3

Figure 10-11. QFN-48 Package Drawing for ATSAM4LC8 and ATSAM4LS8





COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
A	0.80	0.85	0.90	
A1	0.00	0.02	0.05	
A2	0.75	-----	1.00	
D/E		7 BSC		
D2/E2	5.50	5.60	5.70	
L	0.30	0.40	0.50	
b	0.17	-----	0.30	2
e		0.50 BSC		
n		48		

Note: The exposed pad is not connected to anything internally, but should be soldered to ground to increase board level reliability.

Table 10-32. Device and Package Maximum Weight

140	mg

Table 10-33. Package Characteristics

Moisture Sensitivity Level	MSL3

Table 10-34. Package Reference

JEDEC Drawing Reference	MO-220
JESD97 Classification	E3

11. Ordering Information

Table 11-1. ATSAM4LC8 Sub Serie Ordering Information

Ordering Code	Flash (Kbytes)	RAM (Kbytes)	Package	Conditioning	Package Type	Temperature Operating Range
ATSAM4LC8CA-AU	512	64	TQFP100	Tray	Green	Industrial -40°C to 85°C
ATSAM4LC8CA-AUR				Reel		
ATSAM4LC8CA-CFU			VFBGA100	Tray		
ATSAM4LC8CA-CFUR				Reel		
ATSAM4LC8BA-AU			TQFP64	Tray		
ATSAM4LC8BA-AUR				Reel		
ATSAM4LC8BA-MU			QFN64	Tray		
ATSAM4LC8BA-MUR				Reel		
ATSAM4LC8BA-UUR			WLCSP64	Reel		
ATSAM4LC8AA-MU			QFN48	Tray		
ATSAM4LC8AA-MUR				Reel		

Table 11-2. ATSAM4LC4 Sub Serie Ordering Information

Ordering Code	Flash (Kbytes)	RAM (Kbytes)	Package	Conditioning	Package Type	Temperature Operating Range
ATSAM4LC4CA-AU-ES	256	32	TQFP100	ES	Green	N/A
ATSAM4LC4CA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LC4CA-AUR				Reel		
ATSAM4LC4CA-CFU			VFBGA100	Tray		Industrial -40°C to 85°C
ATSAM4LC4CA-CFUR				Reel		
ATSAM4LC4BA-AU-ES			TQFP64	ES		N/A
ATSAM4LC4BA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LC4BA-AUR				Reel		
ATSAM4LC4BA-MU-ES			QFN64	ES		N/A
ATSAM4LC4BA-MU				Tray		Industrial -40°C to 85°C
ATSAM4LC4BA-MUR				Reel		
ATSAM4LC4BA-UUR			WLCSP64	Reel		Industrial -40°C to 85°C
ATSAM4LC4AA-AU-ES			TQFP48	ES		N/A
ATSAM4LC4AA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LC4AA-AUR				Reel		
ATSAM4LC4AA-MU-ES			QFN48	ES		N/A
ATSAM4LC4AA-MU				Tray		Industrial -40°C to 85°C
ATSAM4LC4AA-MUR				Reel		